



325 Washington Avenue Ext., Albany, NY 12205

Wafer measurement report for customer reference and pre-sales Of Proforma 300iSA

Prepared by: Engineer Name

Date: 10/1/2020

Wafer measurements performed by: Engineer Name, and Senior Engineer

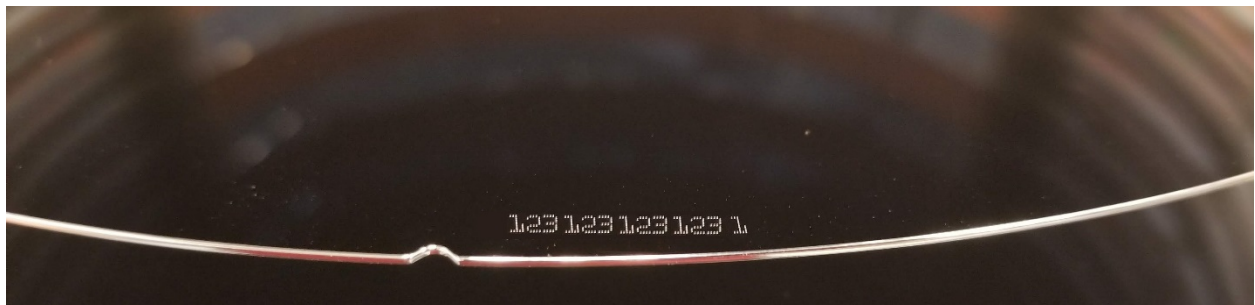
1 Customer information

1.1 Company name: Prospective Customer

1.2 Contact name: John Doe (jdoe@prospective.com)

2 Supplied materials

2.1 FOUP containing the following wafer:



3 Customer supplied instructions/documentation

Wafer Type	Number of wafers to measure	Measurements requested
Flat	1	Standard measurement

5 Results summary

Wafer measurements were carried out as per request. For each measurement, the readings were taken 10 times, this provides more accuracy. Data will show a "Wafer #1" which represents the data for the first of the ten readings and not necessarily different wafers.

Wafer calibration was done using an MTI test wafer with SN: XXXX and center thickness of 728.79 um.

The recipe created for this trial had a 3mm exclusion zone and 8mm circumferential and radial spacing.

5.1 Conclusion

All measurements appear nominal. A comma separated variable file with the raw data has also been provided.